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Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number. Complete if Known Substitute for form 1449/PTO **Application Number** 10/687,519 Filing Date 10/16/2003 INFORMATION DISCLOSURE First Named Inventor Truskett et al. STATEMENT BY APPLICANT Art Unit 1762 (Use as many sheets as necessary) Chen, Bret P. **Examiner Name**

Attorney Docket Number P75-17-03 Sheet 1 **U. S. PATENT DOCUMENTS** Name of Patentee or Pages, Columns, Lines, Where Publication Date Examiner Cite Document Number **Applicant of Cited Document** Relevant Passages or Relevant Initials* No. MM-DD-YYYY Figures Appear Number-Kind Code^{2 (I known)} 2005/0064344-A1 3/24/2005 J1 Bailey et al. ^{US-} 2005/0082253-A1 4/21/2005 J2 Cherala et al. ^{US-} 2005/0051698-A1 J3 3/10/2005 Sreenivasan et al. ^{US-} 2005/0074512-A1 4/7/2005 McMackin et al. **J**4 ^{US-} 2005/0072757-A1 4/7/2005 McMackin et al. J5 ^{US-} 2005/0072755-A1 4/7/2005 McMackin et al. **J**6 US- 2004/0170770-A1 9/2/2004 Nguyen et al. J7 US- 2004/0256764-A1 J8 12/23/2004 Choi et al. US- 2004/0146792-A1 7/29/2004 Nimmakayala et al. J9 US- 6,955,868-B2 J10 10/18/2005 Choi et al.

Sreenivasan

Sreenivasan et al.

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Application Number	10/687,519			
Filing Date	10/16/2003			
First Named Inventor	Truskett et al.			
Art Unit	1762			
Examiner Name	Chen, Bret P.			
Attorney Docket Number	P.75-17-03			
	Filing Date First Named Inventor Art Unit Examiner Name			

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		NON PATENT LITERATURE DOCUMENTS	
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	J17	Willson et al., "Step and Elash Imprint Lithography," U.S. Patent Application 10/806,051, filed with UPSTO March 22, 2004	
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				U.S. PATENT DOCUMEN	TS	
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^{&#}x27;Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

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				Group Art Unit	1762	
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Sheet	3	of	4	Attorney Docket Number	P75-17-03	

OTHER PRIOR	R ART -	NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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Signature Considered *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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				Application Number	10/687,519		
INF	ORMATION	DISC	CLOSURE	Filing Date	10/16/2003		
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Sheet	4	of	4	Attorney Docket Number	P75-17-03		

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Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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	Π.	U.S. Patent Do	ocument	1	Date of Publication of	Pages, Columns, Lines,
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Sheet	2	of	9	Examiner Name	Turner, Archene A. C	
				Attorney Docket Number	P75-17-03	

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Substitute fo	or form 1449A/	РТО		Complete if Known		
*	FORMATION ATEMENT E			APPLICATION NUMBER	10/687,519	
31	AI EMENT) AFFEIG	- And I	FILING DATE	10/16/2003	
(us	e as many sheet	s as necessar _i	v)	FIRST NAMED INVENTOR	Truskett et al.	
				Group Art Unit	2775 1762	
Sheet	4	of	9	Examiner Name	Turner, Archene A. C.	
-	•			Attorney Docket Number	P75-17-03	

OTHER PRI	OR ART -	NON PATENT LITERATURE DOCUMENTS
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published:
$\mathbb{W}/\!\!/\!\!/$	140	BLOMQUIST ET AL., Fluorinated Acrylates in making Low-Loss, Low-Birefringence, and Single-Mode Optical Waveguides with Exceptional Thermo-Optic Properties, SPIE Conference on Linear Optical Properties of Waveguides and Fibers, Vol. 3799, pp. 266 - 279 7/1/1999
	141	BENDER ET AL., Fabrication of Nanostructures using a UV-based Imprint Technique, Microelectronic Engineering 53, pp. 233 -236 1/1/2000
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	145	HIRAI ET AL., Abstract of Mold Surface Treatment for Imprint Lithography, Journal of Photopolymer Science and Technology, pp 457-462, vol 14, No. 3 8/1/2001
	146	ROOS ET AL., Abstract of Nanoimprint Lithography with a Commercial 4 Inch Bond System for Hot Embossing, Proceedings of SPIE Vol. 4343, pp. 427-435 10/1/2001
Ā	147	PAPIRER ET AL., The Grafting of Perfluorinated Silanes onto the Surface of Silica: Characterization by Inverse Gas Chromatography, Journal of Colloid and Interface Science 159, pp.238-242 8/1/1993
	148	Sol-Gel Technology, www.chemat.com/html/solgel.html 1/14/2004
Examiner Signature		Date Considered

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	ORMATION			APPLICATION NUMBER	10/687,519	
317	41EMENT C	T APPLIC	ANI	FILING DATE	10/16/2003	
(use	as many sheets	s as necessar,	v)	FIRST NAMED INVENTOR	Truskett et al.	
				Group Art Unit	1775 1762	
Sheet	5	of	9	Examiner Name	Turner, Archene A:	
		•		Attorney Docket Number	P75-17-03	

inne	Cita	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the	_
Examiner nitials*	Cite No.	item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
A	γ		
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1	150	HAKOVIRTA ET AL., Optical Properties of Fluorinated Diamond-Like Carbon Films Produced by Pulsed Glow Discharge Plasma Immersion Ion Processing, Journal of Applied Physics 88(3); pp1456-1459 8/1/2000	
	151	ARPLICATION NO. 10/827,118, naming Inventors Watts et al., entitled A Method of Foreing a Deep-Featured Template Employed in Imprint Lithography, filed 4/19/2004	
	152	APPLICATION NO. 10/789,319, naming Inventors Xu et al., entitled Composition for an Etching Mask Comprising a Silicon-Containing Material, filed 2/27/2004	• • •
-	153	APPLICATION NO. 10/919,062, naming Inventor Xu et al., entitled Composition to Provide a Lyaer with Uniform Etch Characteristics, filed 8/16/2004	7
	154	APPLICATION NO. 11/012,374, naming Inventors Xu et al., entitled Composition to Reduce Adhesion Between a Conformable Region and a Mold, filed 12/15/2004	
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<u> </u>	156	Data Sheet for MAK (Methyl n-Amyl Ketone), www.sp-chem.com/fine_e 1/1/2003	
17	157	Data Sheet for gamma-Glycidoxypropyltrimethoxysilane, www.powerchemical.net/3100.htm 12/5/2003	
Examiner		Date //	

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¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached. This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending on the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450.. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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	FORMATION ATEMENT B			APPLICATION NUMBER	10/687,519	
31	AICHENIC	T APPLIC	ANI	FILING DATE	10/16/2003	
(use	e as many sheet	s as necessary	v)	FIRST NAMED INVENTOR	Truskett et al.	
				Group Art Unit	1775 M62	
Sheet	6	of	9	Examiner Name	Aurner, Archene A.	
				Attorney Docket Number	P75-17-03	

OTHER PRIC	OR ART -	NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
11/11			
	158	Silicon or Silica, www.mii.org/Minerals/photosil 3/31/2005	
	159	Electronic Devices and Circuits, people.deas.harvard.edu/~jones/es154/lectures/lecture_2/materials/materials.html 3/31/2005	
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	1 71	 	 <u> </u>
Examiner Signature	\bigcup	Date Considered	

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	FORMATION ATEMENT B	_	_	APPLICATION NUMBER	10/687,519		
31	AIEMENIE	T APPLIC	ANI	FILING DATE	10/16/2003		
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				Group Art Unit	1775-1762		
Sheet	7	of	9	Examiner Name	Turner, Archene A.Ch.		
	<u>* </u>	•		Attorney Docket Number	P75-17-03		

OTHER PRIC	OR ART	- NON PATENT LITERATURE DOCUMENTS	
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·	168	Abstract of Japanese Patent 02-248480, 10/4/1990	
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V	172	Abstract of Japanese Patent 02-248480, 10/4/1990	
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M	174	XU ET AL., Development of Imprint Materials for the Step and Flash Imprint Lithography Process, SPIE Microlithography Conference 2/1/2004	
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Examiner Signature Date Considered		Δ	L	·		
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	FORMATION ATEMENT B			APPLICATION NUMBER	10/687,519
	AI CINCINI	TAITEIO.	7 41	FILING DATE	10/16/2003
(us	e as many sheets	s as necessary	<i>)</i>	FIRST NAMED INVENTOR	Truskett et al.
				Group Art Unit	2775 1762
Sheet 8		of	9	Examiner Name	Turner, Archene A.
		<u>*</u>		Attorney Docket Number	P75-17-03

Examiner nitials* /	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
	•		
	176	DAUKSHER ET AL., Repair of Step and Flash Imprint Lithography Templates, J. Vac. Sci. Technol. B 22(6), pp. 3306-3311 11/1/2004	
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31	AIEMENI D	1 APPLIC	AUTI	FILING DATE	10/16/2003		
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				Group Art Unit	2775 1762		
Sheet	9	of	9	Examiner Name	Turner, Archene A. C		
				Attorney Docket Number	P75-17-03		

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	185	BAILEY ET AL., Template Fabrication Schemes for Step and Flash Imprint Lithography, Microelectronic Engineering, 61-62, pp. 461-467 1/1/2002								
1	186	RESNICK ET AL., High Resolution Templates for Step and Flash Imprint Lithography, SPIE Microlithography Conference 2/1/2002								
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Title of Invention

LOW SURFACE ENERGY TEMPLATES

Application Number:

10/687519

Confirmation Number:

5222

First Named Applicant:

Van Truskett

Attorney Docket Number:

P75-17-03

Art Unit:

1775

Examiner:

Archene A. Turner

Search string:

(6468642 or 5542978 or 5837314 or 6565776 or 6503914 or 6649272 or 6204343 or 4614667 or 3810874 or 6737489 or 6721529 or 6664306 or 6790905 or 6544594

or 6774183 or 6830819 or 6802870 or 5389696).pn

US Patent Documents

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J	/t	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
\mathbb{W}		1	6468642	2002-10-22	Bray et al.	B1	/	1
M		2	5542978	1996-08-06	Kindt-Larsen et al.			
Ш		3	5837314	1998-11-17	Beaton et al.			
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Γ		12	6664306	2003-12-16	Gaddam et al.	B2		
		13	6790905	2004-09-14	Fitzgerald et al.	B2		
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		. 17	6802870	2004-10-12	Chang et al.	B2		/
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